Effects of Ionization on Beam Parallel Component and Beam-Driven Perpendicular Modes

- Experiments¹ indicate beam-driven mode in the vicinity of the ion cyclotron frequency (n = 1)seen at low β —conditions typically found in C2U
- 1D PIC simulations with ion beam reproduce ion
- Velocity-space broadening by ionization may create population of beam ions with increased parallel velocity component.
- This work explores the effect of ionization of a neutral beam on perpendicular beam-driven modes and the creation of more strongly parallel beam ions in a uniform magnetic field.

- that $v_h \ll v_{Te}$.

$$\langle v_e \sigma(v_e) \rangle = \left(\frac{2}{\pi}\right)$$





B ₀	T _{i,e}
0.075 T	200 eV

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